



International initiative on x-ray fundamental parameters

Advantages of being an active member of the FP initiative:

1. learn about the international status of FP data including critical evaluations by experts and needs with respect to novel technological applications (such as in nanolayered systems)
2. actively contribute to the international FP roadmap generation including its updating process, e.g. to have the optimal reference document for your financial applications
3. identify colleagues with whom you together can determine FP parameters in dedicated projects and / or activities
4. learn about novel experimental and theoretical methodologies for improved FP parameters determinations

Selected achievements in 2011 to 2014:

5. several European Metrology Research Programme (EMRP) projects including FP determinations - EMRP ThinFilms, TRenD and ThinErgy (further projects under the follow-up programme EMPIR being prepared)
6. dissemination of FP initiative to North America and Japan by means of workshops at NIST and NIMS, respectively.
7. comparison of recent theoretical calculations and metrological experiments, see e.g. PRA 89, 012512 (2014) and PRL 113, 163001(2014)
8. involvement in recent high-resolution experiments and systematic MAC determinations
9. database of FP related literature established and updated
10. access to full FP initiative resources granted to more than 100 FP workshop attendees